

# NEW PRODUCT NEWS

## NEW TOPCON SM-520 FIELD EMISSION SEM - FIELD-EMISSION PERFORMANCE AT LAB<sup>s</sup> PRICES.

Topcon's Model SM-520 Field-Emission (FE) SEM offers extremely high spatial resolution and is ideal for a wide range of SEM applications. It is especially suited for low kV, high-resolution applications. Low kV operation allows the user to minimize sample damage and charging. With the SM-520 FE SEM, the user does not have to sacrifice high resolution because of budget restrictions.

The SM-520 FE SEM includes a sample airlock for easy sample exchange and vacuum protection. It has Topcon's unique Dual Control™ feature, which combines manual and computer operation (each independent of the other), and image processing for bright, clear images. In addition, Topcon's SEMs are computer-hardware independent and can be used with any personal computer. Live images can be viewed in normal room lighting on a 21-inch monitor. A standard image processor with frame averaging is included and it produces clear, crisp, noise-free images at 512, 1024 or 3048 pixel resolution - with unlimited image storage capabilities. Topcon Technologies: (800)538-6850. **Circle Reader Inquiry #30**

Gresham-Camscan introduces the OrTex System for the measurement of crystal orientation and texture analysis. The new OrTex System enables the accurate determination of the orientation and texture of polycrystalline materials, as well as high resolution surface topographic images, high contrast atomic number imaging for orienta-

tion contrast and fully quantitative X-ray analysis of regions and multi-elemental distribution maps.

The OrTex system is designed around a new EBSP detector from Gresham-CamScan, which is interfaced to the microscope specimen chamber. For further information, contact CamScan U.S.A.: (412)772-7433. **Circle Reader Inquiry #31.**

## Advanced Imaging Concepts announces Virtual Color™, a family of products that can turn standard monochrome video and digital cameras into color cameras.

Virtual Color comprises hardware and software products that can combine three sequential, color-filtered acquisitions from a monochrome camera into a single color image. It can capture monochrome images at any wavelength, and it can run on several types of cameras, including scientific CCD, high-resolution CCD, intensified CCD, and cooled CCD units. Advanced Imaging Concepts, Inc.: (908)274-1877. **Circle Reader Inquiry #32.**

## Leica announces two new accessories for the LEICA GZ6 stereomicroscope:

The LEICA GZ6 Coaxial Illumination System is flexible in design, using fiber optic technology to provide a full field, full aperture illumination down to 1.5X and designed for flat specimens with moderate to high reflectivity.

The LEICA GZ6 Image Port System brings video and photomicrography capabilities to the stereomicroscope. Leica, Inc.: (800)248-0123. **Circle Reader Inquiry #33.**



Spectra-Tech, Inc. introduces their patented FT-IR microsampling accessory - the ATR Objective - available exclusively for Spectra-Tech FT-IR and Nicolet Microscopes. This single reflection ATR microscopy optic permits direct analyses of samples such as carbon-filled rubber, polymers, coatings, fibers, semi-solid materials, biological samples, micro-quantities of a liquid, contaminants and samples with low reflectivity. Optically opaque or highly absorbing materials can be analyzed by infrared microscopy with virtually no sample preparation. Samples as small as 10 μm can be analyzed when using with an IR-Plan, IRus or Nic-Plan microscope. Spectra-Tech, Inc.: (203)926-8998. **Circle Reader Inquiry #34**

### USED EQUIPMENT WANTED

✓ Incident-light Microscope Interferometer for the LEITZ ORTHOPLAN. Call Steve Turney at 314-362-2514 or eMail turney\_s@nmj.wustl.edu or write to Washington University, Campus Box 8108, St. Louis, MO 63110.

### USED EQUIPMENT FOR SALE

✓ MILITARY RESEARCH LAB IS CLOSING - Military contractor is selling at drastically reduced prices its Sorvall ultramicrotome, refrigerated and benchtop microtomes, sliding microtome, Tissue Tech embedding center, stereo microscopes, Joyce Loebel microdensitometer and LECO sulfur analyzer. For specification sheets call: (202)544-0836.

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